

April 1988 Revised August 1999

## 74F544

# **Octal Registered Transceiver**

#### **General Description**

The 74F544 octal transceiver contains two sets of D-type latches for temporary storage of data flowing in either direction. Separate Latch Enable and Output Enable inputs are provided for each register to permit independent control of inputting and outputting in either direction of data flow. The A outputs are guaranteed to sink 24 mA while the B outputs are rated for 64 mA. The 74F544 inverts data in both directions.

#### **Features**

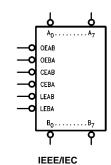
- 8-bit octal transceiver
- Back-to-back registers for storage
- Separate controls for data flow in each direction
- A outputs sink 24 mA, B outputs sink 64 mA

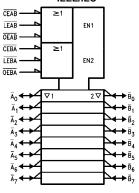
### **Ordering Code:**

Order Number	Package Number	Package Description
74F544SC	M24B	24-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-013, 0.300 Wide
74F544MSA	MSA24	24-Lead Shrink Small Outline Package (SSOP), EIAJ TYPE II, 5.3mm Wide
74F544SPC	N24C	24-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-100, 0.300 Wide

Devices also available in Tape and Reel. Specify by appending the suffix letter "X" to the ordering code.

## **Logic Symbols**





# **Connection Diagram**



# **Unit Loading/Fan Out**

Din Names	December 1	U.L.	Input I <sub>IH</sub> /I <sub>IL</sub>	
Pin Names	Description	HIGH/LOW	Output I <sub>OH</sub> /I <sub>OL</sub>	
OEAB	A-to-B Output Enable Input (Active LOW)	1.0/1.0	20 μA/-0.6 mA	
OEBA	B-to-A Output Enable Input (Active LOW)	1.0/1.0	20 μA/-0.6 mA	
CEAB	A-to-B Enable Input (Active LOW)	1.0/2.0	20 μA/–1.2 mA	
CEBA	B-to-A Enable Input (Active LOW)	1.0/2.0	20 μA/–1.2 mA	
LEAB	A-to-B Latch Enable Input (Active LOW)	1.0/1.0	20 μA/-0.6 mA	
LEBA	B-to-A Latch Enable Input (Active LOW)	1.0/1.0	20 μA/-0.6 mA	
$\overline{A}_0 - \overline{A}_7$	A-to-B Data Inputs or	3.5/1.083	70 μΑ/–650 μΑ	
	B-to-A 3-STATE Outputs	150/40(33.3)	-3 mA/24 mA (20 mA)	
$\overline{B}_0 - \overline{B}_7$	B-to-A Data Inputs or	3.5/1.083	70 μΑ/–650 μΑ	
	A-to-B 3-STATE Outputs	600/106.6(80)	-12 mA/64 mA (48 mA)	

#### **Functional Description**

The 74F544 contains two sets of eight D-type latches, with separate input and output controls for each set. For data flow from A to B, for example, the A-to-B Enable  $(\overline{\text{CEAB}})$  input must be LOW in order to enter data from  $\overline{A}_0-\overline{A}_7$  or take data from  $\overline{B}_0-\overline{B}_7$ , as indicated in the Data I/O Control Table. With  $\overline{\text{CEAB}}$  LOW, a LOW signal on the A-to-B Latch Enable ( $\overline{\text{LEAB}}$ ) input makes the A-to-B latches transparent; a subsequent LOW-to-HIGH transition of the LEAB signal puts the A latches in the storage mode and their outputs no longer change with the A inputs. With  $\overline{\text{CEAB}}$  and  $\overline{\text{OEAB}}$  both LOW, the 3-STATE B output buffers are active and reflect the data present at the output of the A latches. Control of data flow from B to A is similar, but using the  $\overline{\text{CEBA}}$ ,  $\overline{\text{LEBA}}$  and  $\overline{\text{OEBA}}$  inputs.

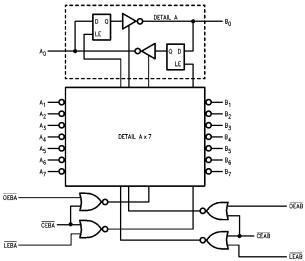
#### **Data I/O Control Table**

Inputs			Latch	Output		
CEAB	LEAB	OEAB	Status	Buffers		
Н	Х	Х	Latched	High Z		
Х	Н	X	Latched	_		
L	L	X	Transparent	_		
Х	Χ	Н	_	High Z		
L	Χ	L	_	Driving		

- H = HIGH Voltage Level
- L = LOW Voltage Level
- X = Immaterial

**Note:** A-to-B data flow shown; B-to-A flow control is the same, except using  $\overline{\text{CEBA}}$ ,  $\overline{\text{LEBA}}$  and  $\overline{\text{OEBA}}$ 

#### **Logic Diagram**



Please note that this diagram is provided only for the understanding of logic operations and should not be used to estimate propagation delays.

## **Absolute Maximum Ratings**(Note 1)

-65°C to +150°C Storage Temperature Ambient Temperature under Bias -55°C to +125°C

Junction Temperature under Bias -55°C to +150°C V<sub>CC</sub> Pin Potential to Ground Pin -0.5V to +7.0VInput Voltage (Note 2) -0.5V to +7.0VInput Current (Note 2) -30 mA to +5.0 mA

Voltage Applied to Output

in HIGH State (with  $V_{CC} = 0V$ )

Standard Output -0.5V to  $V_{CC}$ 3-STATE Output -0.5V to +5.5V

Current Applied to Output

in LOW State (Max) twice the rated I<sub>OL</sub> (mA)

### **Recommended Operating Conditions**

Free Air Ambient Temperature 0°C to +70°C Supply Voltage +4.5V to +5.5V

Note 1: Absolute maximum ratings are values beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.

Note 2: Either voltage limit or current limit is sufficient to protect inputs.

#### **DC Electrical Characteristics**

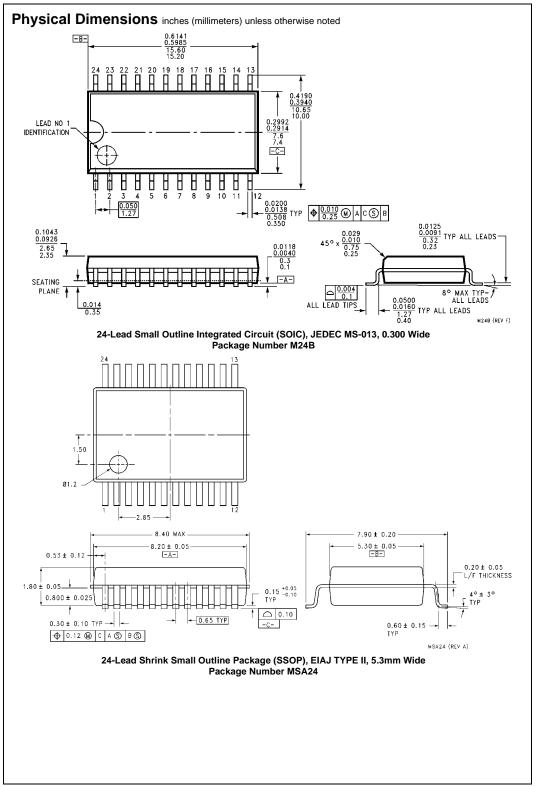
Symbol	Parameter		Min	Тур	Max	Units	v <sub>cc</sub>	Conditions	
V <sub>IH</sub>	Input HIGH Voltage		2.0			V		Recognized as a HIGH Signa	
V <sub>IL</sub>	Input LOW Voltage				0.8	V		Recognized as a LOW Signal	
V <sub>CD</sub>	Input Clamp Diode Voltage				-1.2	V	Min	$I_{IN} = -18 \text{ mA},$ (except $\overline{A}_n$ , $\overline{B}_n$ )	
V <sub>OH</sub>	Output HIGH	10% V <sub>CC</sub>	2.5					$I_{OH} = -1 \text{ mA } (\overline{A}_n)$	
	Voltage	10% V <sub>CC</sub>	2.4					$I_{OH} = -3 \text{ mA } (\overline{A}_n, \overline{B}_n)$	
		10% V <sub>CC</sub>	2.0			V	Min	$I_{OH} = -15 \text{ mA } (\overline{B}_n)$	
		5% V <sub>CC</sub>	2.7					$I_{OH} = -1 \text{ mA } (\overline{A}_n)$	
		5% V <sub>CC</sub>	2.7					$I_{OH} = -3 \text{ mA } (\overline{A}_n, \overline{B}_n)$	
V <sub>OL</sub>	Output LOW	10% V <sub>CC</sub>			0.5	V	Min	$I_{OL} = 24 \text{ mA } (\overline{A}_n)$	
	Voltage	10% V <sub>CC</sub>			0.55	V	Min	$I_{OL} = 64 \text{ mA } (\overline{B}_n)$	
I <sub>IH</sub>	Input HIGH				20.0	^	Max	$V_{IN} = 2.7V \text{ (except } \overline{A}_n, \overline{B}_n)$	
	Current				5.0	μΑ	iviax	$V_{IN} = 2.7V \text{ (except A}_n, B_n)$	
I <sub>BVI</sub>	Input HIGH Current				7.0	μА	Max	$V_{IN} = 7.0V \text{ (except } \overline{A}_n, \overline{B}_n)$	
	Breakdown Test				7.0	μΑ	IVIAX	VIN - 1.04 (except An, Dn)	
I <sub>BVIT</sub>	Input HIGH Current				0.5	mA	Max	$V_{IN} = 5.5 V (\overline{A}_{p_1}, \overline{B}_{p_2})$	
	Breakdown (I/O)				0.0	1117 (	IVIGA	VIN - 0.0 V (/ (n, Dn)	
I <sub>CEX</sub>	Output HIGH				250	μА	Max	$V_{OLIT} = V_{CC} (\overline{A}_{p_1}, \overline{B}_{p_2})$	
	Leakage Current				200	por t	· · · · ·	661 66 ( 11. 11.	
$V_{ID}$	Input Leakage		4.75			V	0.0	$I_{ID} = 1.9 \mu A$	
	Test							All Other Pins Grounded	
l <sub>OD</sub>	Output Leakage				3.75	μΑ	0.0	V <sub>IOD</sub> = 150 mV	
	Circuit Current							All Other Pins Grounded	
I <sub>IL</sub>	Input LOW Current				-0.6	mA	Max	$V_{IN} = 0.5V (\overline{OEAB}, \overline{OEBA})$	
					-1.2			$V_{IN} = 0.5V (\overline{CEAB}, \overline{CEBA})$	
$I_{IH} + I_{OZH}$	Output Leakage Current				70	μΑ	Max	$V_{OUT} = 2.7V (\overline{A}_n, \overline{B}_n)$	
$I_{IL} + I_{OZL}$	Output Leakage Current				-650	μΑ	Max	$V_{OUT} = 0.5V (\overline{A}_n, \overline{B}_n)$	
I <sub>OS</sub>	Output Short-Circuit Current		-60		-150			$V_{OUT} = 0V(\overline{A}_n)$	
			-100		-225	mA N	Max	$V_{OUT} = 0V (\overline{B}_n)$	
I <sub>ZZ</sub>	Bus Drainage Test				500	μΑ	0.0V	$V_{OUT} = 5.25V (\overline{A}_n, \overline{B}_n)$	
I <sub>CCH</sub>	Power Supply Current		1	70	105	mA	Max	V <sub>O</sub> = HIGH	
I <sub>CCL</sub>	Power Supply Current			85	130	mA	Max	$V_O = LOW$	
I <sub>CCZ</sub>	Power Supply Current			83	125	mA	Max	V <sub>O</sub> = HIGH Z	

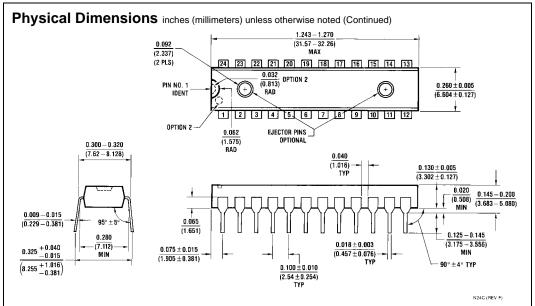
# **AC Electrical Characteristics**

Symbol	Parameter		$T_{A} = +25^{\circ}C$ $V_{CC} = +5.0V$ $C_{L} = 50 \text{ pF}$			$T_{A} = -55 ^{\circ} C \text{ to } +125 ^{\circ} C$ $V_{CC} = +5.0 V$ $C_{L} = 50 \text{ pF}$		$T_A = 0$ °C to +70°C $V_{CC} = +5.0V$ $C_L = 50$ pF	
		Min	Тур	Max	Min	Max	Min	Max	
t <sub>PLH</sub>	Propagation Delay	3.0	7.0	9.5	3.0	12.0	3.0	10.5	
$t_{PHL}$	Transparent Mode	3.0	5.0	6.5	2.5	8.5	3.0	7.5	ns
	$\overline{A}_n$ to $\overline{B}_n$ or $\overline{B}_n$ to $\overline{A}_n$								
t <sub>PLH</sub>	Propagation Delay	6.0	10.0	13.0	6.0	18.0	6.0	14.5	ns
$t_{PHL}$	LEBA to A <sub>n</sub>	4.0	7.0	9.5	4.0	11.5	4.0	10.5	
t <sub>PLH</sub>	Propagation Delay	6.0	10.0	13.0	6.0	18.0	6.0	14.5	
$t_{PHL}$	LEAB to B <sub>n</sub>	4.0	7.0	9.5	4.0	11.5	4.0	10.5	ns
t <sub>PZH</sub>	Output Enable Time	3.0	7.0	9.0	3.0	11.0	3.0	10.0	
$t_{PZL}$	$\overline{\text{OEBA}}$ or $\overline{\text{OEAB}}$ to $\overline{\text{A}}_n$ or $\overline{\text{B}}_n$	4.0	7.5	10.5	4.0	13.0	4.0	12.0	
	$\overline{\text{CEBA}}$ or $\overline{\text{CEAB}}$ to $\overline{\text{A}}_{\text{n}}$ or $\overline{\text{B}}_{\text{n}}$								
t <sub>PHZ</sub>	Output Disable Time	1.0	6.0	8.0	2.0	10.0	1.0	9.0	ns
$t_{PLZ}$	$\overline{OEBA}$ or $\overline{OEAB}$ to $\overline{A}_n$ or $\overline{B}_n$	2.5	5.5	10.5	2.0	9.5	2.5	11.5	
	$\overline{\text{CEBA}}$ or $\overline{\text{CEAB}}$ to $\overline{\text{A}}_{\text{n}}$ or $\overline{\text{B}}_{\text{n}}$								

# **AC Operating Requirements**

Symbol	Symbol Parameter		$T_A = +25^{\circ}C$ $V_{CC} = +5.0V$		$T_A = -55^{\circ}C$ to $+125^{\circ}C$ $V_{CC} = +5.0V$		$T_A = 0$ °C to +70°C $V_{CC} = +5.0V$	
		Min	Max	Min	Max	Min	Max	
t <sub>S</sub> (H)	Setup Time, HIGH or LOW	3.0		3.0		3.0		
t <sub>S</sub> (L)	$\overline{A}_n$ or $\overline{B}_n$ to $\overline{LEBA}$ or $\overline{LEAB}$	3.0		3.0		3.0		
t <sub>H</sub> (H)	Hold Time, HIGH or LOW	3.0		3.0		3.0		ns
t <sub>H</sub> (L)	$\overline{A}_n$ or $\overline{B}_n$ to $\overline{LEBA}$ or $\overline{LEAB}$	3.0		3.0		3.0		
t <sub>W</sub> (L)	Latch Enable, B to A	6.0		9.0		7.5		ns
	Pulse Width, LOW	0.0		9.0		7.5		115





24-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-100, 0.300 Wide Package Number N24C

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